

100V N-Channel MOSFET

General Features

- Proprietary New Planar Technology
- $R_{DS(ON),typ.}$ =17m Ω @ V_{GS} =10V Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode

Applications Automotive

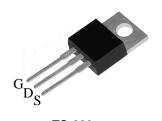
- DC Motor Control

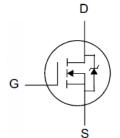
Ordering Information

Part Number	Package	Brand
PTP23N10A	TO-220	ĭ

(PG) Lead Free Package and Finish

BV _{DSS}	$R_{DS(ON),typ.}$	I_{D}
100V	17mΩ	57A





Package No to Scale

Absolute Maximum Ratings

 $T_C=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	PTP23N10A	Unit	
V_{DSS}	Drain-to-Source Voltage	100	V	
V _{GSS}	Gate-to-Source Voltage	±20	V	
I _D	Continuous Drain Current	57	Α	
I _{DM}	Pulsed Drain Current at V _{GS} =10V	Figure 6		
E _{AS}	Single Pulse Avalanche Energy	1000	mJ	
D	Power Dissipation	200	W	
P _D	Derating Factor above 25℃	1.3	W/℃	
T _L	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300	°C	
T _J & T _{STG}	Operating and Storage Temperature Range	-55 to 175	C	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	PTP23N10A	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	0.75	20.44
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	°C/W



Electrical Characteristics

OFF Characteristics T_J =25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	100			٧	V _{GS} =0V, I _D =250uA
I _{DSS} Drain-to-Source Leakage Current	Design to Course Lorden a Course			1	V _{DS} =100V, V _{GS} =0V	
			100	uA	V_{DS} =80V, V_{GS} =0V, T_J =125°C	
	Cata to Source Leekage Current			+100	nΛ	V _{GS} =+20V, V _{DS} =0V
I _{GSS}	Gate-to-Source Leakage Current			-100	nA	V _{GS} =-20V, V _{DS} =0V

ON Characteristics

T_J =25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
R _{DS(ON)}	Static Drain-to-Source On-Resistance		17	23	mΩ	V _{GS} =10V, I _D =28A
V _{GS(TH)}	Gate Threshold Voltage	2.0		4.0	٧	$V_{DS}=V_{GS}$, $I_{D}=250uA$
gfs	Forward Transconductance		85		S	Vps=15V,lp=28A

Dynamic Characteristics

Essentially independent of operating temperature

<i>y</i>		ating temperature				
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
C _{iss}	Input Capacitance		2700			V 0V
C _{rss}	Reverse Transfer Capacitance		260		pF	V_{GS} =0V, V_{DS} =25V, f =1.0MH $_{Z}$
C _{oss}	Output Capacitance		610			
Qg	Total Gate Charge		105			
Q _{gs}	Gate-to-Source Charge		15		nC	V_{DD} =50V, I_{D} =28A, V_{GS} =0 to 10V
Q_{gd}	Gate-to-Drain (Miller) Charge		45			

Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
td(ON)	Turn-on Delay Time		20			
trise	Rise Time		28		20	V _{DD} =50V, I _D =28A,
td(OFF)	Turn-Off Delay Time		65		nS	V_{GS} = 10V RG=2.5 Ω
tfall	Fall Time		15			



Source-Drain Body Diode Characteristics

 $T_J=25^{\circ}\mathbb{C}$ unless otherwise specified

Symbol	Parameter	Min	Тур.	Max.	Unit	Test Conditions
I _{SD}	Continuous Source Current ^[2]			57	۸	Integral PN-diode in
I _{SM}	Pulsed Source Current ^[2]			230	Α	MOSFET
V _{SD}	Diode Forward Voltage			1.5	V	I _S =28A, V _{GS} =0V
trr	Reverse recovery time		195		ns	IF=28A,
Qrr	Reverse recovery charge		107		nC	dir/dt=100A/µs

Note:

^[1] T_J =+25°C to +150°C

^[2] Pulse width≤380µs; duty cycle≤2%.



Typical Characteristics

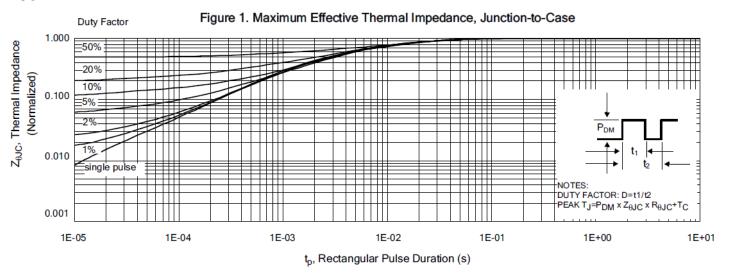


Figure 2. Maximum Power Dissipation vs Case Temperature

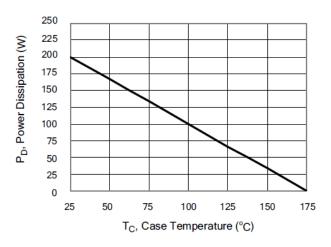


Figure 4. Typical Output Characteristics

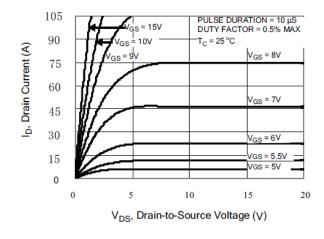


Figure 3. Maximum Continuous Drain Current vs Case Temperature

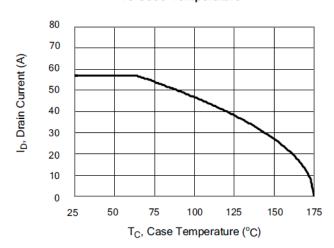
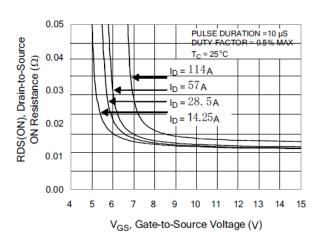


Figure 5. Typical Drain-to-Source ON Resistance vs Gate Voltage and Drain Current





Typical Characteristics(Cont.)

Figure 6. Maximum Peak Current Capability

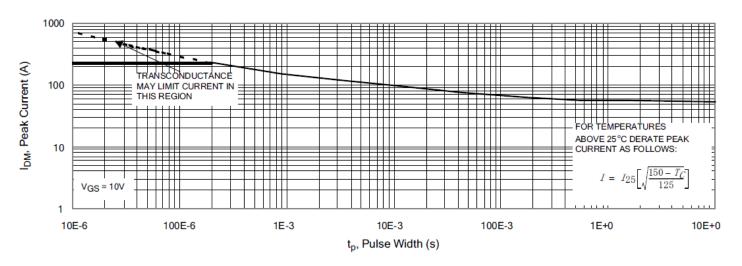


Figure 7. Typical Transfer Characteristics

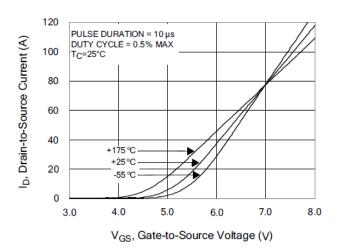


Figure 9. Typical Drain-to-Source ON Resistance vs Drain Current

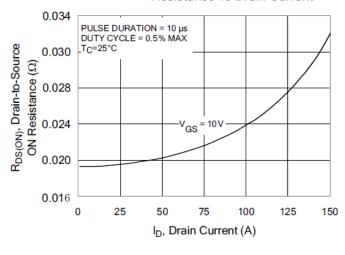


Figure 8. Unclamped Inductive Switching Capability

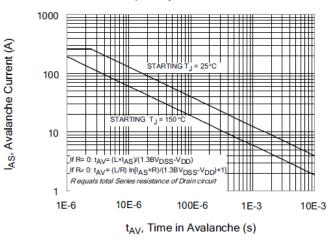
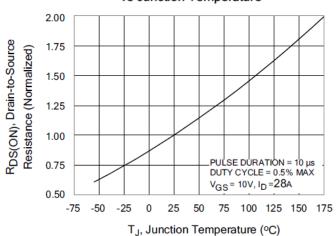


Figure 10. Typical Drain-to-Source ON Resistance vs Junction Temperature





Typical Characteristics(Cont.)

Junction Temperature 1.15

Figure 11. Typical Breakdown Voltage vs

Breakdown Voltage (Normalized) BV_{DSS}, Drain-to-Source 1.10 1.05 1.00 0.95 $V_{GS} = 0V$ $I_D = 250 \, \mu A$ 0.90 75 100 125 150 175 50 -50 -25 0.0 25 T_{.I}, Junction Temperature (°C)

Maximum Forward Bias Safe Figure 13. Operating Area

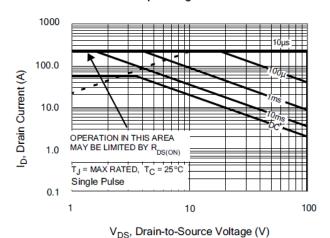


Figure 15 . Typical Gate Charge

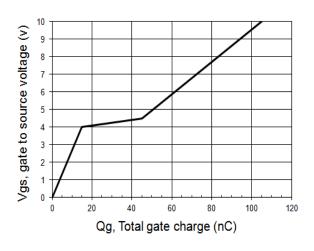


Figure 12. Typical Threshold Voltage vs Junction Temperature

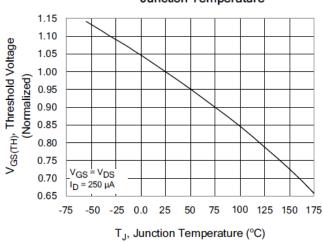


Figure 14. Capacitance vs Vds

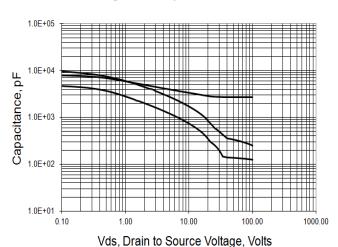
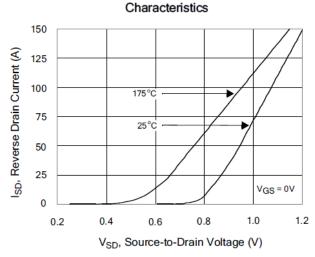


Figure 16. Typical Body Diode Transfer





Test Circuits and Waveforms

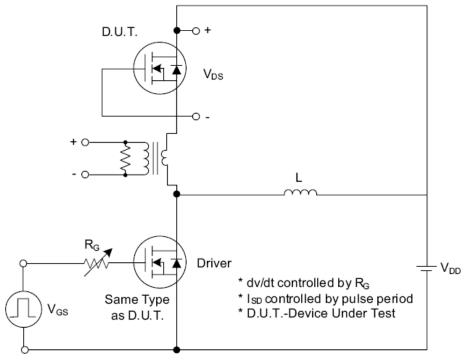


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

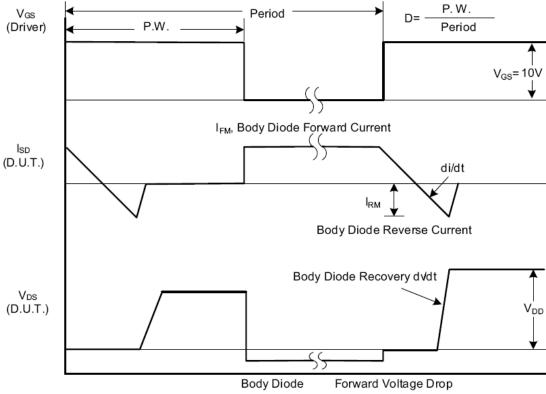


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms



Test Circuits and Waveforms (Cont.)

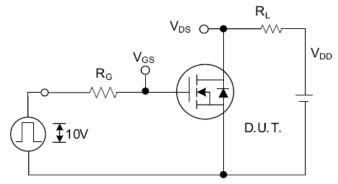


Fig. 2.1 Switching Test Circuit

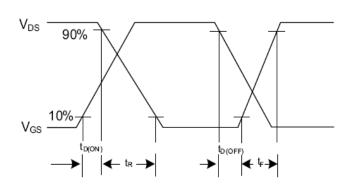


Fig. 2.2 Switching Waveforms

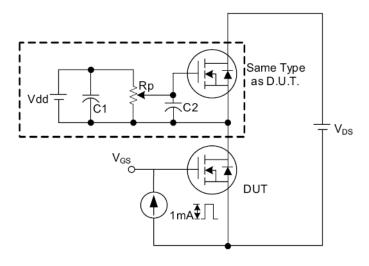


Fig. 3 . 1 Gate Charge Test Circuit

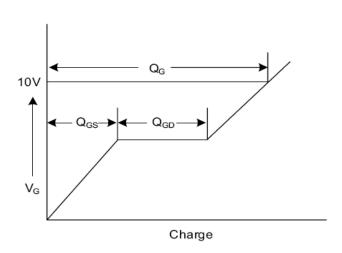


Fig. 3.2 Gate Charge Waveform

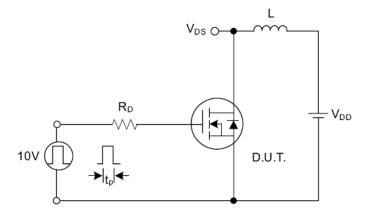


Fig. 4.1 Unclamped Inductive Switching Test Circuit

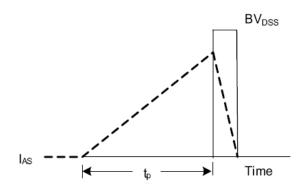


Fig. 4.2 Unclamped Inductive Switching Waveforms



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